

Ivan
Candlish
(A)

Sent to ERIW

29 July 1976.

From
Robert W. Harrison.

29 July 1977

"Major ^{Detector} Considerations", Trade-offs, etc. Concerning
Detector Choice for the NRAO Optical Processor

R. Harrison

① A major problem affecting CCD detectors (but not the Reticon devices) is that of charge transfer efficiency, η which is defined as the fraction of charge actually passed in a given transfer. About the best we could hope this number to be for the Fairchild devices is 0.99999 [this is the best value obtained for any CCD to my knowledge but a much more realistic value would be in the range 0.99997 to 0.99995, which are values actually measured on Fairchild CCD1's (1728 elements)]¹

The effect of these numbers is not negligible in the case of data shifted from the far end of a Fairchild CCD131, with 1024 elements. Even though the charge packet from the most distant photocells travel through a register of only ~ 512 cells, the register is two phase, (i.e. 2 transfers per cell) implying ~ 1024 transfers all told.

The effect of various values of $\epsilon \equiv 1 - \eta$ are shown in Fig 1. Suppose we initially start with the normalized charge distribution across 7 photocells as shown by the solid. This pattern corresponds roughly to the main lobe of a sinc function, with 6 photocells between first zeros. Now transfer this pattern from the far end of a CCD131 (direction of transfer is to the right) and then superimpose the transferred and original patterns to show the degradation.

The dashed line represents the transferred pattern with $\epsilon = 5 \times 10^{-5}$, the dotted line with $\epsilon = 1 \times 10^{-5}$ (Ascon

29 July 1976

was taken of the fact odd and even photocells have different shift registers)

Note the following:

- ① The sizes of the errors (each box represents $\approx 2\%$ the maximum original signal).
- ② The errors are systematic, and will be in addition to uncertainties due to noise. (which has been ignored in the above problem)
- ③ The errors are signal dependent, even if ϵ is independent of signal.

It is clear ϵ in general, will depend on signal, and although a strong dependence of ϵ on signal has been disproved the data could not rule out weak dependences of, say, $\leq 10\%$, which would further complicate matters.

It should be investigated if going to a shorter CCD cures the problem sufficiently.

② As far as a problem with Fabry-Perot type fringing in layers above the photosites, more problem might be encountered with Fairchild, because instead of having a single layer of SiO_2 , they have two layers of SiO_2 with a polysil photocatalytic layer sandwiched in between.

③ Blooming (the spilling of an over-saturated signal from one photosite to another) is apparently much more prevalent in CCD's than in photodiode arrays, because of spillage from an overexposed cell over the potential barrier into adjacent shift register.

29 July 1976

(4) The major cause of nonlinear response (wrt. exposure of both CCD's and photodiodes appears to be in the amplifying electronics, and not the photosensing process itself. In the case of Fairchild, we have to take the on-chip preamp. They give us. On chip preamps of this type have been known to give trouble.² No one to my knowledge has done sufficiently accurate linearity measurements on the Fairchild devices to check the problem at a level we would be interested in.

It is also important to consider the possibility that the reciprocity between time and intensity is good enough for our purposes (ie, is exposing for time t at intensity I the same as exposing for time t/c at intensity (I) . Many linearity measurements are done by varying t to change the exposure (keeping I constant) because it is much easier to do than the other way), but for our device, all integration times will be the same, with a change in I the thing we measure.

(5) The dependence of S/N ratio on exposure is significantly different for the Reticon and CCD devices. This arises from the fact photon noise plays a more significant role in the noise of the CCDs than the photodiode arrays. At saturation, the CCD's can "hold" only about 10^6 photons, while the Reticon devices "hold" about 10^7 .

(6) The Fairchild CCD's make more efficient use of laser energy because

29 July 1976

(D)

(a) The cells cover a smaller area

(b) The noise-equivalent exposure is lower in the Fairchild CCD than the Reticon devices.

Because of these two effects roughly 17 times as much energy will be spent overcoming detector noise in Reticon RL 1872F as compared with the Fairchild CCD 131

(7) The CCD has a more efficient scan method due to the parallel transfer of integrated photosite charge to the analog shift registers as opposed to serial readout

(8) I have not yet found anyone who has tried to measure precisely the photometric properties of the current Fairchild devices, or tried to use them for radiometry.

Reticon, on the other hand, has several customers who have evaluated their devices for such considerations.

(9) Thought should be given to the use of GE CT-D's as detectors.

(10) See list of obvious important detector parameters, things to be tested for, etc.

References:

1 Michael Vicars - Harris, "Slow Scan Operation of Long Linear CCD Arrays," Proceedings: Symposium on Charge-Coupled Device Technology for Scientific Imaging Applications. Date of Publ. 10 July date of Symposium: 6-7 March '75

N 75-28824 thru N 75-28844

Contract NAS 7-100

NASA-CR-100-221

TOP SECRET

29 July 1976

(E)

Refs. cont'd

2 C. H. Séquin and M. F. Tompsett, Charge Transfer Devices (Advances in Electronics and Electron Physics, Supplement 8, 197

© 1975, Academic Press, pp 126, 127

① Existence of Fabry-Pérot type fringing; its dependence on λ and angle of incidence. Can it be calibrated out as a "fixed sensitivity variation for our application?"

② (Dynamic Range)₁ = $\frac{\text{saturation output}}{\text{RMS noise on ave. pixel in dark}}$ = DR₁

Does not include sensitivity variations, dark current non-uniformities, or other fixed pattern "noise"

(Dynamic Range)₂ = $\frac{\text{saturation output}}{\text{amp. of fixed pattern "noise"}}$ = DR₂

③ Can fixed pattern be removed by calibration and filtering and/or current integration so that DR₁ ≈ DR₂ ?

④ Device capacity (i.e. # photons a single pixel can record, as determined by its saturation charge)

⑤ Geometric arrangement of photoelements Existence of crosstalk between adjacent photoelements Dependence on λ With what fidelity (defined in an appropriate manner) does device reproduce the intensity pattern sensed

29 July 1976

(F)

- ① What is dark current, its nonuniformities, and dependence on temp.?
- ② Are nonuniformities in sensitivity from photoelement photoelement independent of intensity, and thus can be calibrated out?
- ③ How good is the temporal stability of key device parameters, and what are the effects of any changes or device calibration?
Is it necessary to regulate the temperature to obtain sufficient stability for reasonable calibration?
- ④ If cooling is necessary for reduction of dark current what are the effects on device operation as a whole?
- ⑤ Whether or not "blooming" occurs with photoelements exposed beyond saturation. How bad?
- ⑥ Whether or not there is a "threshold" exposure level
- ⑦ How fast and slow can the array be scanned? What is mode of scanning?
- ⑧ How is linearity of output w.r.t. both intensity and time. Is there a reciprocity failure analogous to photographic film? If nonlinear, can it easily be corrected for to better than 1% cumulative error over 3 orders of mag. in intensity?
- ⑨ Be aware of possible nonlinearities in readout electronics

29 July 1976

(6)

(5) How complete is the readout? Is it a func. of clock freq. or exposure level? How is linearity affected?